

ABSTRACT

Tools, systems and/or methods for use in a test process of a circuit device. Such tools, systems and/or methods may provide for identifying respective parent and branch portions of a scan chain of a circuit device, the scan chain having at least one scan input and one or more scan outputs and a plurality of scan cells; and creating a model of the scan chain, including creating a dummy cell chain which includes a branch portion of the scan chain and has one or more dummy cells disposed therein connected between the branch portion and the scan input.